

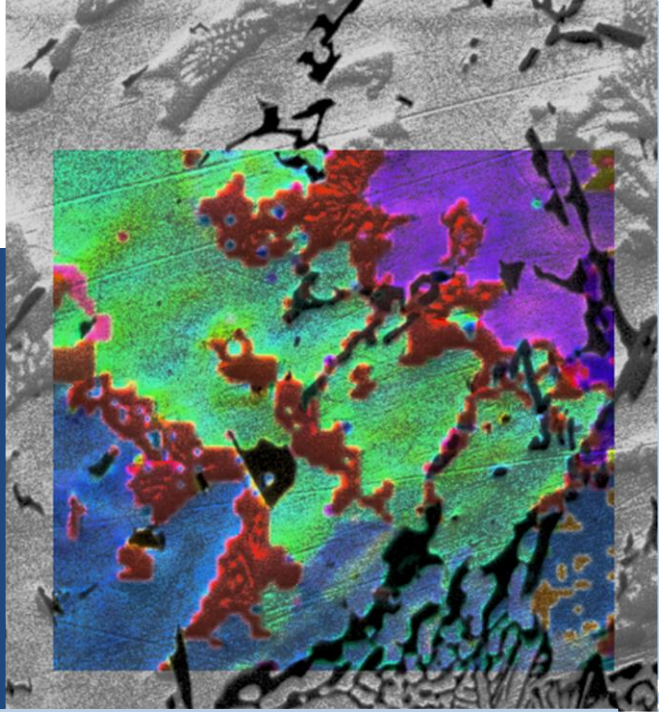


Industry meets Academia

## EBSD Training School

28.04.-29.04.2015

Espoo, Finland



### Training School Content

Electron BackScatter Diffraction Analysis in the Scanning Electron Microscope imposes requirements on both research equipment and operator at the same time. The objective of the training school is to prepare EBSD-users for day-to-day measurement routine and to lay the foundation of independent problem solving capability. Topics cover everything from the basics of crystallography, to choice of analysis parameters, their influence on measurement progress and out-come, as well as the different graphical tools of representing orientation data and texture information. The course provides problem solving strategies for a variety of industrially and academically relevant topics in a mix of lectures, demos and exercise:

1. Basics of crystallography
2. Formation of electron backscatter pattern and their interpretation
3. Stereographic & gnomonic projection
4. Description of crystal orientation
5. Description of texture
6. Sample preparation
7. Setting up for EBSD-analysis
8. Influence of experimental parameters

9. Error Sources
10. Simultaneous EBSD/ EDS analysis
11. Advanced EBSD methods

### Target Group

Researchers and technical assistants from industry, research institutes, universities or public institutions who want to start up, brush up or deepen their knowledge or practical experience in all areas of crystallographic microstructure analysis and phase characterization using the SEM.

### Training school manager

Dr. Sven Curtze

### Place

Aalto University, Puumiehenkuja 3, Espoo, Finland.

### Price and sign-up

The training school fee is 800 € (excl. VAT). Please sign up at [www.nacon.fi](http://www.nacon.fi) or return the sign-up form via e-mail to [info@nacon.fi](mailto:info@nacon.fi).

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